



# M36L0T7050T2 M36L0T7050B2

## 128 Mbit (Multiple Bank, Multi-Level, Burst) Flash memory and 32 Mbit (2Mb x16) PSRAM, Multi-Chip Package

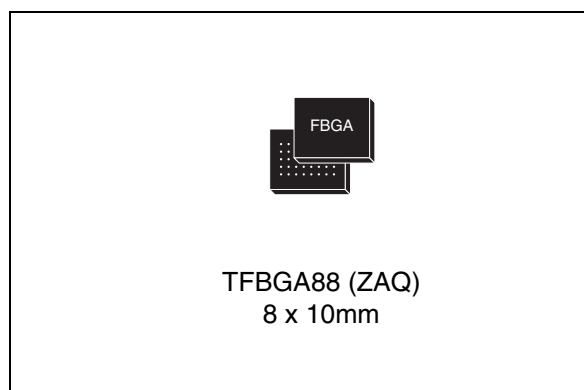
Preliminary Data

### Feature summary

- Multi-Chip Package
  - 1 die of 128 Mbit (8Mb x16, Multiple Bank, Multi-level, Burst) Flash Memory
  - 1 die of 32 Mbit (2Mb x16) Pseudo SRAM
- Supply voltage
  - $V_{DDF} = 1.7$  to  $1.95V$
  - $V_{CCP} = V_{DDQ} = 2.7$  to  $3.1V$
  - $V_{PPF} = 9V$  for fast program
- Electronic signature
  - Manufacturer Code: 20h
  - Device Code (Top Flash Configuration)  
M36L0T7050T2: 88C4h
  - Device Code (Bottom Flash Configuration)  
M36L0T7050B2: 88C5h
- ECOPACK® packages available

### Flash memory

- Synchronous / Asynchronous Read
  - Synchronous Burst Read mode: 52MHz
  - Random Access: 85ns
- Synchronous Burst Read Suspend
- Programming time
  - 2.5 $\mu$ s typical Word program time using Buffer Enhanced Factory Program command
- Memory organization
  - Multiple Bank Memory Array: 8 Mbit Banks
  - Parameter Blocks (Top or Bottom location)
- Dual operations
  - program/erase in one Bank while read in others
  - No delay between read and write operations



- Block locking
  - All blocks locked at power-up
  - Any combination of blocks can be locked with zero latency
  - $\overline{WP}$  for Block Lock-Down
  - Absolute Write Protection with  $V_{PP} = V_{SS}$
- Security
  - 64 bit unique device number
  - 2112 bit user programmable OTP Cells
- Common Flash Interface (CFI)
- 100,000 program/erase cycles per block

### PSRAM

- Access time: 65ns
- 8-Word Page Access capability: 18ns
- Low standby current: 100 $\mu$ A
- Deep power down current: 10 $\mu$ A
- Compatible with standard LPSRAM
- Power-down modes
  - Deep Power-Down
  - 4 Mbit Partial Array Refresh
  - 8 Mbit Partial Array Refresh

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# 1 Summary description

The M36L0T7050T2 and M36L0T7050B2 combine two memory devices in a Multi-Chip Package:

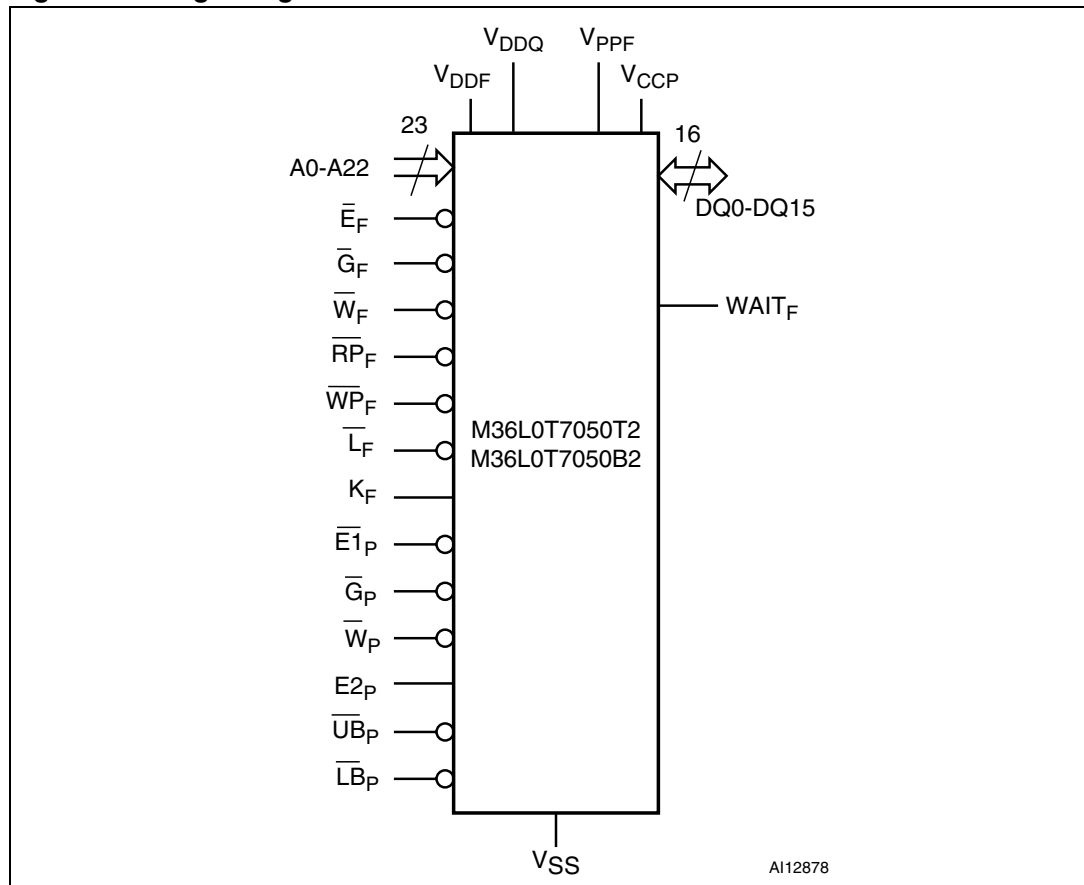
- a 128-Mbit, Multiple Bank, Multi-Level, Burst, Flash memory, the M58LT128HT or M58LT128HB
- a 32-Mbit PseudoSRAM, the M69KW048BD.

The purpose of this document is to describe how the two memory components operate with respect to each other. It should be read in conjunction with the M58LT128HTB and M69KW048BD datasheets, where all specifications required to operate the Flash memory and PSRAM components are fully detailed. These datasheets are available from your local Numonyx distributor.

Recommended operating conditions do not allow more than one memory to be active at the same time.

The memory is offered in a Stacked TFBGA88 (8 x 10mm, 8x10 ball array, 0.8mm pitch) package. The devices are supplied with all the bits erased (set to '1').

**Figure 1. Logic diagram**

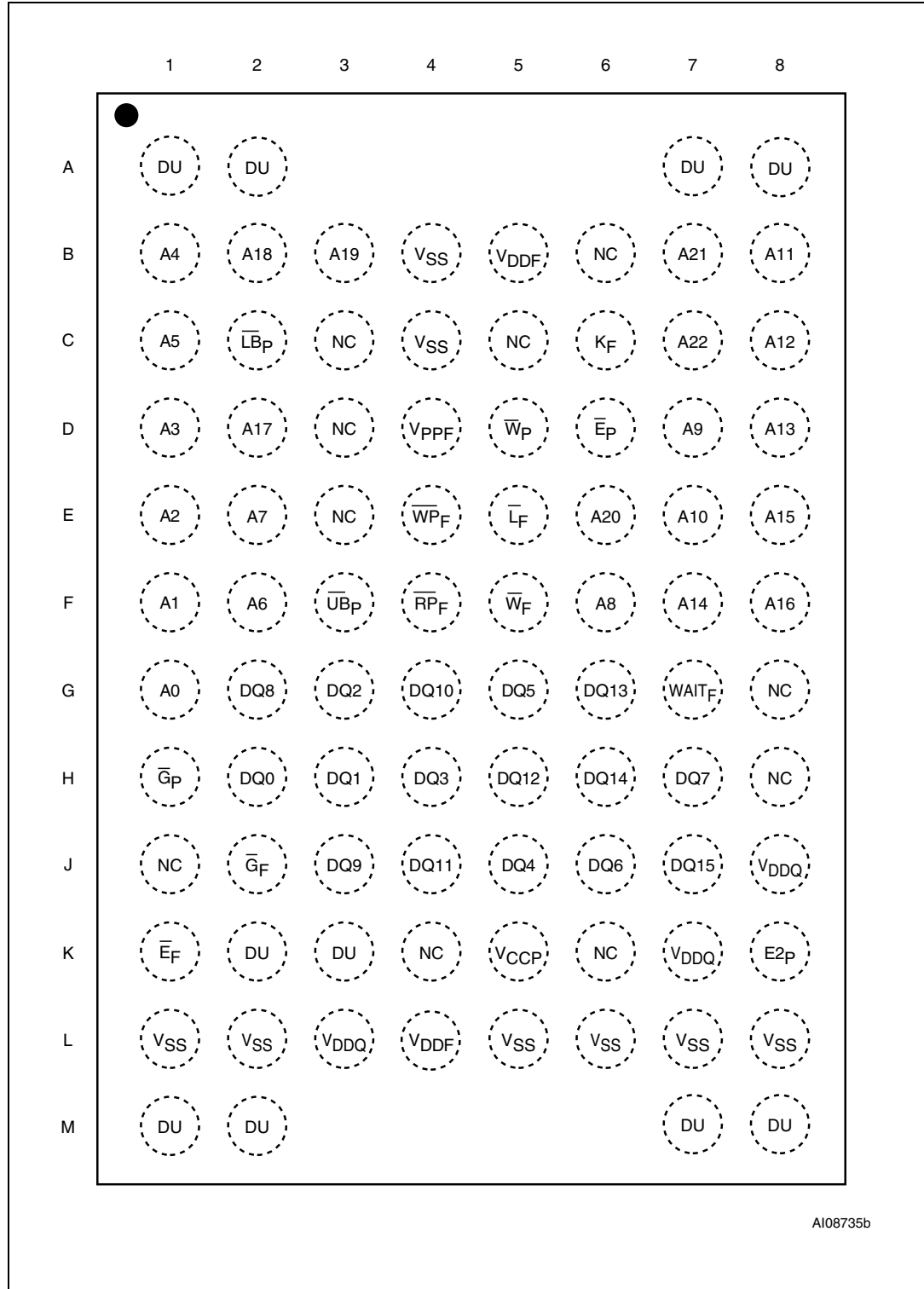


**Table 1. Signal names**

A0-A22 <sup>(1)</sup>	Address Inputs
DQ0-DQ15	Common Data Input/Output
V <sub>DDF</sub>	Power Supply for Flash Memory
V <sub>DDQ</sub>	Flash Memory Power Supply for I/O Buffers
V <sub>PPF</sub>	Flash Optional Supply Voltage for Fast Program and Erase
V <sub>SS</sub>	Ground
V <sub>CCP</sub>	PSRAM Power Supply
NC	Not Connected Internally
DU	Do Not Use as Internally Connected
<b>Flash memory signals</b>	
$\overline{L}_F$	Latch Enable Input
$\overline{E}_F$	Chip Enable Input
$\overline{G}_F$	Output Enable Input
$\overline{W}_F$	Write Enable Input
$\overline{RP}_F$	Reset Input
$\overline{WP}_F$	Write Protect Input
K <sub>F</sub>	Burst Clock
WAIT <sub>F</sub>	Wait Data in Burst Mode
<b>PSRAM signals</b>	
$\overline{E1}_P$	Chip Enable Input
$\overline{G}_P$	Output Enable Input
$\overline{W}_P$	Write Enable Input
E2 <sub>P</sub>	Power-down Input
$\overline{UB}_P$	Upper Byte Enable Input
$\overline{LB}_P$	Lower Byte Enable Input

1. A22-A21 are not connected to the PSRAM component.

Figure 2. TFBGA Connections (Top view through package)





## 2 Signal descriptions

See [Figure 1: Logic diagram](#) and [Table 1: Signal names](#), for a brief overview of the signals connected to this device.

### 2.1 Address Inputs (A0-A22)

Addresses A0-A20 are common inputs for the Flash memory and the PSRAM components. The other lines (A21-A22) are inputs for the Flash memory component only.

The Address Inputs select the cells in the memory array to access during Bus Read operations. During Bus Write operations they control the commands sent to the Command Interface of the Program/Erase Controller in the Flash memory, and they select the cells to be accessed in the PSRAM.

### 2.2 Data Input/Output (DQ0-DQ15)

In the Flash memory, the Data I/O outputs the data stored at the selected address during a Bus Read operation or inputs a command or the data to be programmed during a Write Bus operation.

In the PSRAM DQ0-DQ7 and/or DQ8-DQ15 carry the data to or from the upper and/or lower part(s) of the selected address during a Write or Read operation, when Upper Byte Enable ( $\overline{UB}_P$ ) and/or Lower Byte Enable ( $\overline{LB}_P$ ) is/are driven Low.

### 2.3 Flash Chip Enable ( $\overline{E}_F$ )

The Chip Enable input activates the memory control logic, input buffers, decoders and sense amplifiers. When Chip Enable is Low,  $V_{IL}$ , and Reset is High,  $V_{IH}$ , the device is in active mode. When Chip Enable is at  $V_{IH}$  the Flash memory is deselected, the outputs are high impedance and the power consumption is reduced to the standby level.

It is not allowed to set  $\overline{E}_F$  at  $V_{IL}$ ,  $\overline{E1}_P$  at  $V_{IL}$  and  $E2_P$  at  $V_{IH}$  at the same time.

### 2.4 Flash Output Enable ( $\overline{G}_F$ )

The Output Enable input controls data output during Flash memory Bus Read operations.

### 2.5 Flash Write Enable ( $\overline{W}_F$ )

The Write Enable controls the Bus Write operation of the Flash memories' Command Interface. The data and address inputs are latched on the rising edge of Chip Enable or Write Enable whichever occurs first.

## 2.6 Flash Write Protect ( $\overline{WP}_F$ )

Write Protect is an input that gives an additional hardware protection for each block. When Write Protect is Low,  $V_{IL}$ , Lock-Down is enabled and the protection status of the Locked-Down blocks cannot be changed. When Write Protect is at High,  $V_{IH}$ , Lock-Down is disabled and the Locked-Down blocks can be locked or unlocked. (See the Lock Status Table in the M58LT128HTB datasheet).

## 2.7 Flash Reset ( $\overline{RP}_F$ )

The Reset input provides a hardware reset of the memory. When Reset is at  $V_{IL}$ , the memory is in Reset mode: the outputs are high impedance and the current consumption is reduced to the Reset Supply Current  $I_{DD2}$ . Refer to M58LT128HTB datasheet for the value of  $I_{DD2}$ . After Reset all blocks are in the Locked state and the Configuration Register is reset. When Reset is at  $V_{IH}$ , the device is in normal operation. Exiting Reset mode the device enters Asynchronous Read mode, but a negative transition of Chip Enable or Latch Enable is required to ensure valid data outputs.

The Reset pin can be interfaced with 3V logic without any additional circuitry. It can be tied to  $V_{RPH}$  (refer to M58LT128HTB datasheet).

## 2.8 Flash Latch Enable ( $\overline{L}_F$ )

Latch Enable latches the address bits on its rising edge. The address latch is transparent when Latch Enable is Low,  $V_{IL}$ , and it is inhibited when Latch Enable is High,  $V_{IH}$ . Latch Enable can be kept Low (also at board level) when the Latch Enable function is not required or supported.

## 2.9 Flash Clock ( $K_F$ )

The Clock input synchronizes the Flash memory to the microcontroller during synchronous read operations; the address is latched on a Clock edge (rising or falling, according to the configuration settings) when Latch Enable is at  $V_{IL}$ . Clock is don't care during Asynchronous Read and in write operations.

## 2.10 Flash Wait ( $WAIT_F$ )

WAIT is a Flash output signal used during Synchronous Read to indicate whether the data on the output bus are valid. This output is high impedance when Flash Chip Enable is at  $V_{IH}$  or Flash Reset is at  $V_{IL}$ . It can be configured to be active during the wait cycle or one clock cycle in advance. The  $WAIT_F$  signal is not gated by Output Enable.

## 2.11 PSRAM Chip Enable Input ( $\overline{E1}_P$ )

When asserted (Low), the Chip Enable,  $\overline{E1}_P$  activates the memory state machine, address buffers and decoders, allowing Read and Write operations to be performed. When de-asserted (High), all other pins are ignored, and the device is put, automatically, in low-power Standby mode.

It is not allowed to set  $\overline{E}_F$  at  $V_{IL}$ ,  $\overline{E1}_P$  at  $V_{IL}$  and  $E2_P$  at  $V_{IH}$  at the same time.

## 2.12 PSRAM Chip Enable Input ( $E2_P$ )

The Chip Enable,  $E2_P$ , puts the device in Deep Power-down mode when it is driven Low. This is the lowest power mode.

## 2.13 PSRAM Write Enable ( $\overline{W}_P$ )

The Write Enable,  $\overline{W}_P$ , controls the Bus Write operation of the memory.

## 2.14 PSRAM Output Enable ( $\overline{G}_P$ )

The Output Enable,  $\overline{G}_P$ , provides a high speed tri-state control, allowing fast read/write cycles to be achieved with the common I/O data bus.

## 2.15 PSRAM Upper Byte Enable ( $\overline{UB}_P$ )

The Upper Byte Enable,  $\overline{UB}_P$ , gates the data on the Upper Byte Data Inputs/Outputs (DQ8-DQ15) to or from the upper part of the selected address during a Write or Read operation.

## 2.16 PSRAM Lower Byte Enable ( $\overline{LB}_P$ )

The Lower Byte Enable,  $\overline{LB}_P$ , gates the data on the Lower Byte Data Inputs/Outputs (DQ0-DQ7) to or from the lower part of the selected address during a Write or Read operation.

## 2.17 $V_{DDF}$ Supply Voltage

$V_{DDF}$  provides the power supply to the internal cores of the Flash memory component. It is the main power supply for all Flash operations (Read, Program and Erase).

## 2.18 $V_{CCP}$ Supply Voltage

The  $V_{CCP}$  Supply Voltage supplies the power for all operations (Read or Write) and for driving the refresh logic, even when the device is not being accessed.

## 2.19 $V_{DDQ}$ Supply Voltage

$V_{DDQ}$  provides the power supply for the Flash memory I/O pins. This allows all Outputs to be powered independently of the Flash Memory core power supply,  $V_{DDF}$ .

## 2.20 $V_{PPF}$ Program Supply Voltage

$V_{PPF}$  is both a Flash control input and a Flash power supply pin. The two functions are selected by the voltage range applied to the pin.

If  $V_{PPF}$  is kept in a low voltage range (0V to  $V_{DDQ}$ )  $V_{PPF}$  is seen as a control input. In this case a voltage lower than  $V_{PPLKF}$  gives an absolute protection against Program or Erase, while  $V_{PPF} > V_{PP1}$  enables these functions (see the M58LT128HTB datasheet for the relevant values).  $V_{PPF}$  is only sampled at the beginning of a Program or Erase; a change in its value after the operation has started does not have any effect and Program or Erase operations continue.

If  $V_{PPF}$  is in the range of  $V_{PPH}$  it acts as a power supply pin. In this condition  $V_{PPF}$  must be stable until the Program/Erase algorithm is completed.

## 2.21 $V_{SS}$ Ground

$V_{SS}$  is the common ground reference for all voltage measurements in the Flash (core and I/O Buffers) and PSRAM chips.

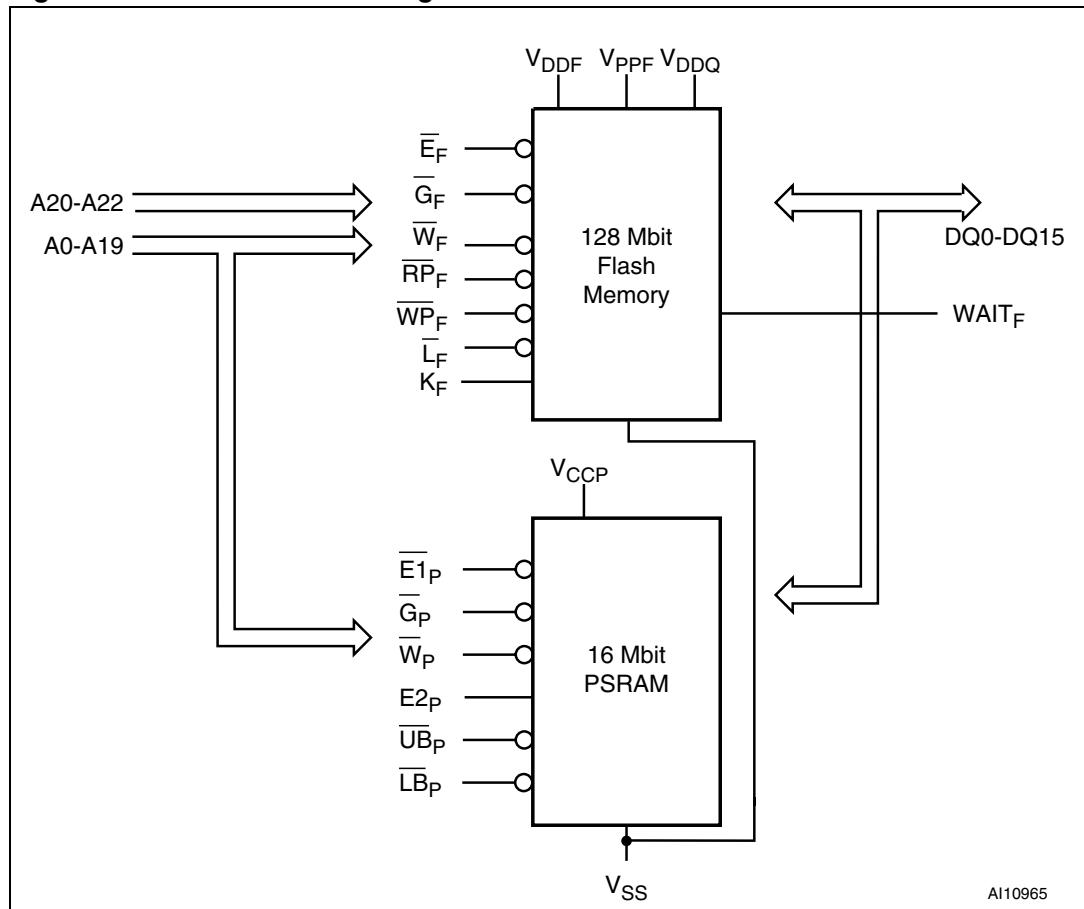
*Note: The Flash memory device in a system should have their supply voltage ( $V_{DDF}$ ) and the program supply voltage  $V_{PPF}$  decoupled with a 0.1 $\mu$ F ceramic capacitor close to the pin (high frequency, inherently low inductance capacitors should be as close as possible to the package). See [Figure 5: AC measurement load circuit](#). The PCB track widths should be sufficient to carry the required  $V_{PPF}$  program and erase currents.*

### 3 Functional description

The PSRAM and Flash memory components have separate power supplies but share the same grounds. They are distinguished by three Chip Enable inputs:  $\overline{E}_F$  for the Flash memory and  $\overline{E1}_P$  and  $E2_P$  for the PSRAM.

Recommended operating conditions do not allow more than one device to be active at a time. The most common example is simultaneous read operations in the Flash memory and the PSRAM which would result in a data bus contention. Therefore it is recommended to put the other device in the high impedance state when reading the selected device.

**Figure 3. Functional block diagram**



**Table 2. Operating modes<sup>(1)</sup>**

Operation	$\overline{E}_F$	$\overline{G}_F$	$\overline{W}_F$	$\overline{L}_F$	$\overline{R}_P$	WAIT <sub>F</sub> <sup>(2)</sup>	$\overline{E1}_P$	E2 <sub>P</sub>	$\overline{G}_P$	$\overline{W}_P$	$\overline{LB}_P$	$\overline{UB}_P$	DQ0-DQ7	DQ8-DQ15
Flash Read	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub> <sup>(3)</sup>	V <sub>IH</sub>		PSRAM must be disabled						Data Out	
Flash Write	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub> <sup>(3)</sup>	V <sub>IH</sub>								Data In	
Flash Address Latch	V <sub>IL</sub>	X	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>								Data Out or Hi-Z <sup>(4)</sup>	
Flash Output Disable	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	X	V <sub>IH</sub>	Hi-Z	Any PSRAM mode is allowed						Hi-Z	
Flash Standby	V <sub>IH</sub>	X	X	X	V <sub>IH</sub>	Hi-Z							Hi-Z	
Flash Reset	X	X	X	X	V <sub>IL</sub>	Hi-Z							Hi-Z	
PSRAM Read <sup>(5)</sup>	Flash Memory must be disabled						V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	data out	Hi-Z
							V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Hi-Z	data out
PSRAM Write <sup>(5)</sup>							V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	data out	
							V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	data in	Hi-Z
							V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Hi-Z	data in
							V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub> <sup>(6)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	data in	
PSRAM Output Disabled <sup>(5)</sup>	Any Flash mode is allowed						V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	Hi-Z	
PSRAM Standby (Deselected)							V <sub>IH</sub>	V <sub>IH</sub>	X	X	X	Hi-Z		
PSRAM Power-Down <sup>(7)</sup>							X	V <sub>IL</sub>	X	X	X	Hi-Z		

- X = Don't care.
- WAIT signal polarity is configured using the Set Configuration Register command. See the M58LT128HTB datasheet for details.
- $\overline{L}_F$  can be tied to V<sub>IH</sub> if the valid address has been previously latched.
- Depends on  $\overline{G}_F$ .
- Should not be kept in this logic condition for a period longer than 1µs.
- $\overline{G}_P$  can be V<sub>IL</sub> during the Write operation if the following conditions are satisfied:
  - Write pulse is initiated by  $\overline{E1}_P$  ( $\overline{E1}_P$  Controlled Write timing), or cycle time of the previous operation cycle is satisfied;
  - $\overline{G}_P$  stays V<sub>IL</sub> during the entire Write cycle.
- Power-Down mode can be entered from Standby state and all Data outputs are in High-Z. The Power-Down current and data retention depend on the selection of Power-Down programming.

## 4 Maximum rating

Stressing the device above the rating listed in the Absolute Maximum Ratings table may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the Numonyx SURE Program and other relevant quality documents.

**Table 3. Absolute maximum ratings**

Symbol	Parameter	Value		Unit
		Min	Max	
$T_A$	Ambient Operating Temperature	-25	85	°C
$T_{BIAS}$	Temperature Under Bias	-25	85	°C
$T_{STG}$	Storage Temperature	-55	125	°C
$V_{IO}$	Input or Output Voltage	-0.5	3.6	V
$V_{DDF}$	Flash Memory Core Supply Voltage	-0.2	2.5	V
$V_{DDQ}, V_{CCP}$	PSRAM and Input/Output Supply Voltages	-0.2	3.6	V
$V_{PPF}$	Flash Program Voltage	-0.2	10	V
$I_O$	Output Short Circuit Current	-	100	mA
$t_{VPPFH}$	Time for $V_{PPF}$ at $V_{PPFH}$		100	hours

## 5 DC and AC parameters

This section summarizes the operating measurement conditions, and the DC and AC characteristics of the device. The parameters in the DC and AC characteristics Tables that follow, are derived from tests performed under the Measurement Conditions summarized in [Table 4: Operating and AC measurement conditions](#). Designers should check that the operating conditions in their circuit match the operating conditions when relying on the quoted parameters.

**Table 4. Operating and AC measurement conditions**

Parameter	Flash Memories		PSRAM		Unit
	Min	Max	Min	Max	
V <sub>DDF</sub> Supply Voltage	1.7	1.95	–	–	V
V <sub>CCP</sub> Supply Voltage	–	–	2.7	3.1	V
V <sub>DDQ</sub> Supply Voltage	2.7	3.1	–	–	V
V <sub>PPF</sub> Supply Voltage (Factory environment)	8.5	9.5	–	–	V
V <sub>PPF</sub> Supply Voltage (Application environment)	–0.4	V <sub>DDQ</sub> +0.4	–	–	V
Ambient Operating Temperature	–25	85	–30	85	°C
Load Capacitance (C <sub>L</sub> )	30		50		pF
Output Circuit Resistors (R <sub>1</sub> , R <sub>2</sub> )	22		22		kΩ
Input Rise and Fall Times		5	5		ns
Input Pulse Voltages	0 to V <sub>DDQ</sub>		0 to V <sub>DDQ</sub>		V
Input and Output Timing Ref. Voltages	V <sub>DDQ</sub> /2		V <sub>DDQ</sub> /2		V

**Figure 4. AC Measurement I/O Waveform**

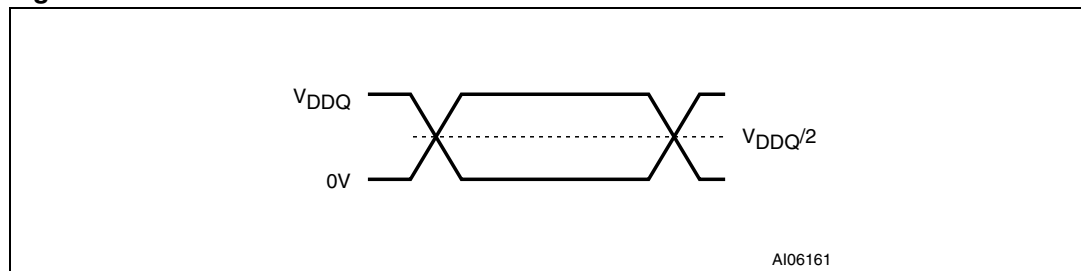




Figure 5. AC measurement load circuit

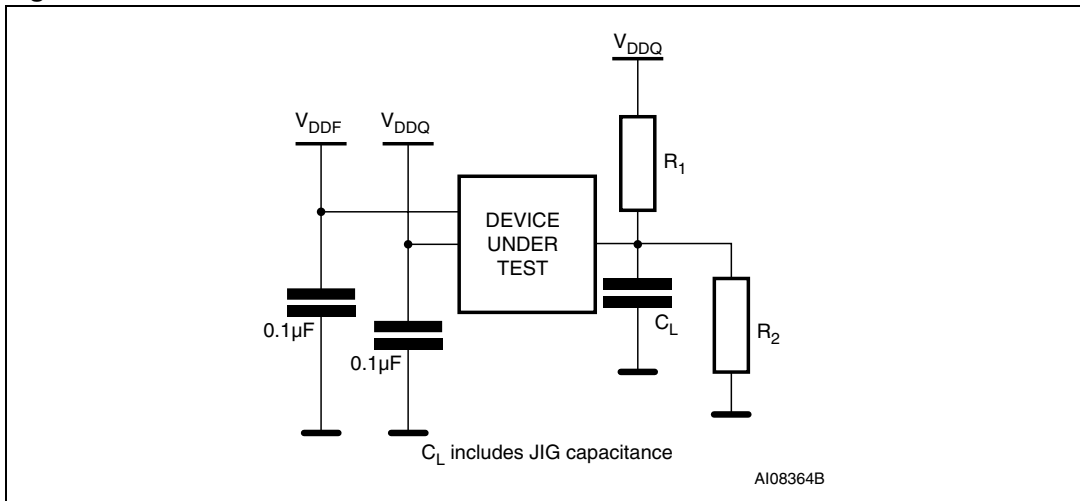


Table 5. Device Capacitance<sup>(1)</sup>

Symbol	Parameter	Test Condition	Min	Max	Unit
$C_{IN}$	Input Capacitance	$V_{IN} = 0V$		12	pF
$C_{OUT}$	Output Capacitance	$V_{OUT} = 0V$		15	pF

1. Sampled only, not 100% tested.

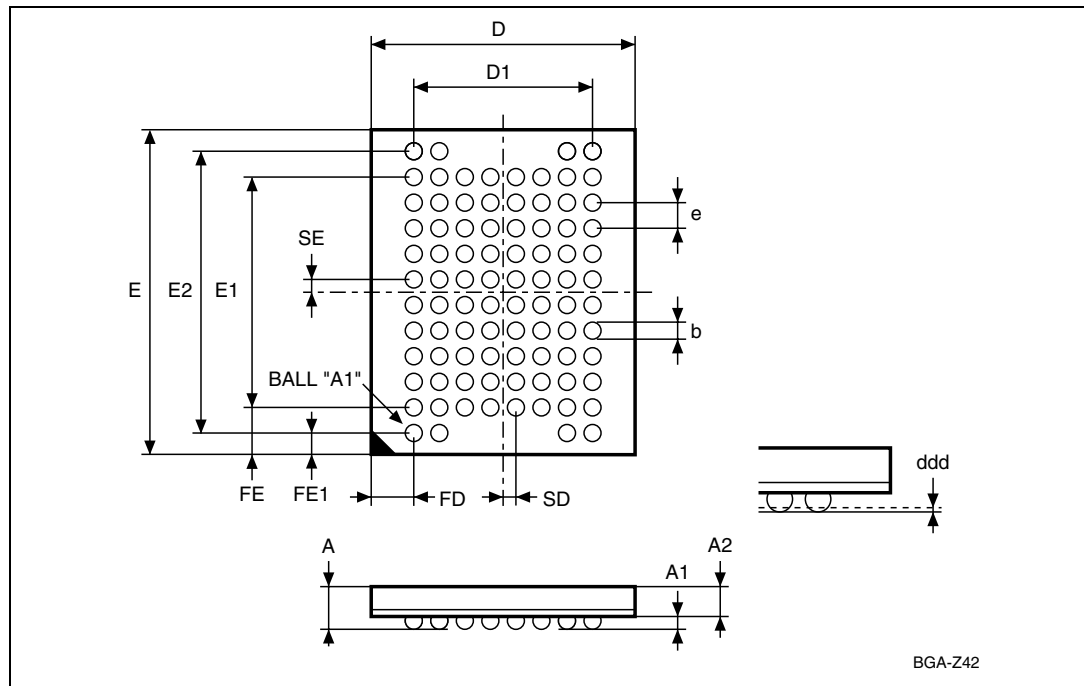
Please refer to the M58LT128HTB and M69KW048BD datasheets for further DC and AC characteristic values and illustrations.

## 6 Package mechanical

In order to meet environmental requirements, Numonyx offers these devices in ECOPACK® packages. These packages have a Lead-free second-level interconnect. The category of Second-Level Interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97.

The maximum ratings related to soldering conditions are also marked on the inner box label.

**Figure 6. Stacked TFBGA88 8x10mm - 8x10 active ball array, 0.8mm pitch, Bottom View Outline**



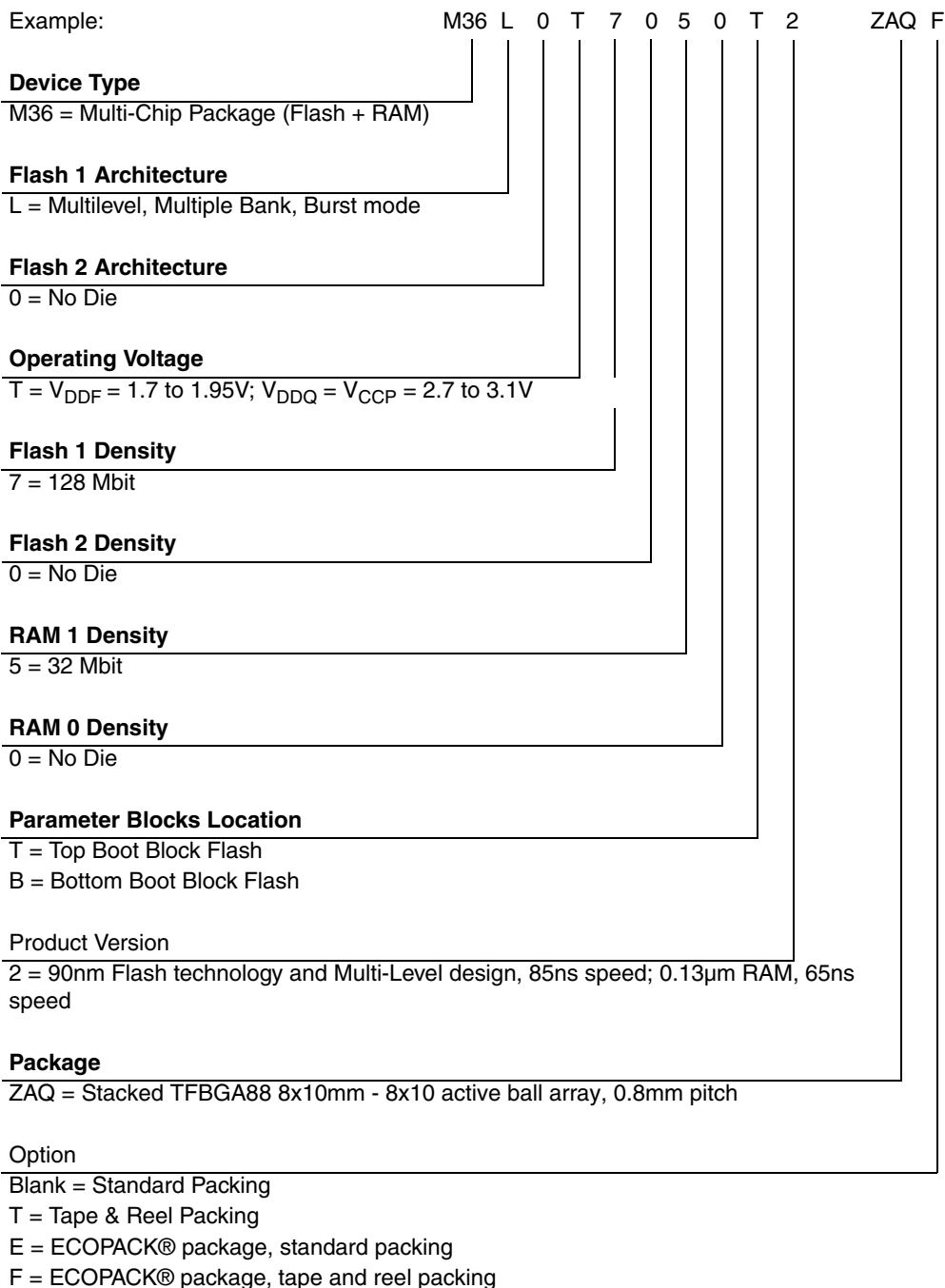
1. Drawing is not to scale.

Table 6. Stacked TFBGA88 8x10mm - 8x10 active ball array, 0.8mm pitch, Package Data

Symbol	millimeters			inches		
	Typ	Min	Max	Typ	Min	Max
A			1.200			0.0472
A1		0.200			0.0079	
A2	0.850			0.0335		
b	0.350	0.300	0.400	0.0138	0.0118	0.0157
D	8.000	7.900	8.100	0.3150	0.3110	0.3189
D1	5.600			0.2205		
ddd			0.100			0.0039
E	10.000	9.900	10.100	0.3937	0.3898	0.3976
E1	7.200			0.2835		
E2	8.800			0.3465		
e	0.800	–	–	0.0315	–	–
FD	1.200			0.0472		
FE	1.400			0.0551		
FE1	0.600			0.0236		
SD	0.400			0.0157		
SE	0.400			0.0157		

# 7 Part numbering

**Table 7. Ordering information scheme**



Devices are shipped from the factory with the memory content bits erased to '1'. For a list of available options (Speed, Package, etc.) or for further information on any aspect of this device, please contact the Numonyx Sales Office nearest to you.

## 8 Revision history

**Table 8. Document revision history**

Date	Revision	Changes
04-May-2006	01	Initial release.
13-Nov-2007	02	Applied Numonyx branding.

**Please Read Carefully:**

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